OPEN COLLECTOR POSITIVE-NAND GATE

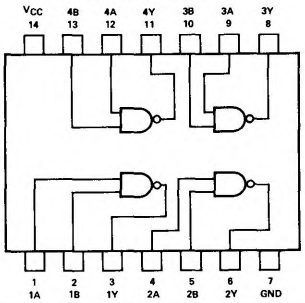
S54S00
S54S03
N74S00
N74S03

S54S00/503–A,F • N74S00/503–A,F

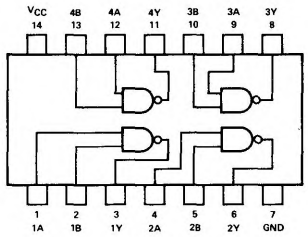
DIGITAL 54/74 TTL SERIES

PIN CONFIGURATIONS

W PACKAGE

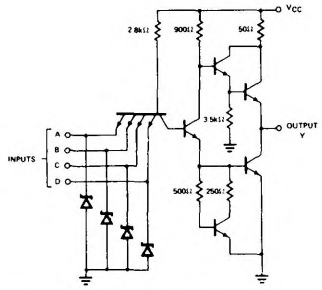


A,F PACKAGE



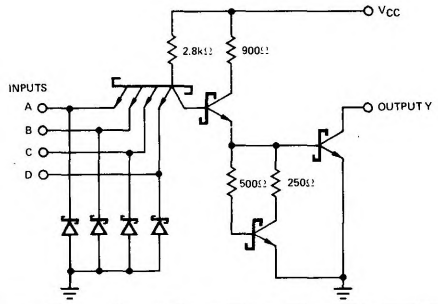
SCHEMATIC (each gate)

S54/N74S00



NOTE:
Component values shown are nominal.

S54/N74S03



RECOMMENDED OPERATING CONDITIONS

	S54S00			N74S00			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply Voltage V_{CC}	4.5	5	5.5	4.75	5	5.25	V
Normalized Fan-Out from each Output, N: High logic level			20			20	
Low logic level			10			10	
Operating Free-Air Temperature, T_A	-55		125	0		70	°C

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS *			MIN	TYP **	MAX	UNIT
V_{IH}	High-level input voltage				2			V
V_{IL}	Low-level input voltage						0.8	V
V_I	Input clamp voltage	V_{CC} = MIN,	I_I = -18mA				-1.2	V
V_{OH}	High-level output voltage	V_{CC} = MIN,	V_{IL} = 0.8V,	Series 54S	2.5	3.4		V
		I_{OH} = -1mA		Series 74S	2.7	3.4		V
V_{OL}	Low-level output voltage	V_{CC} = MIN, I_{OL} = 20mA	V_{IH} = 2V,				0.5	V
I_I	Input current at maximum input voltage	V_{CC} = MAX,	V_I = 5.5V				1	mA
I_{IH}	High-level input current (each input)	V_{CC} = MAX,	V_I = 2.7V				50	μA
I_{IL}	Low-level input current (each input)	V_{CC} = MAX,	V_I = 0.5V				-2	mA
I_{OS}	Short-circuit output current †	V_{CC} = MAX			-40		-100	mA
I_{CCH}	Supply current, high-level output (average per gate)	V_{CC} = MAX,	All inputs at 0V			2.5	4	mA
I_{CCL}	Supply current, low-level output (average per gate)	V_{CC} = MAX,	All inputs at 5V			5	9	mA

SWITCHING CHARACTERISTICS, V_{CC} = 5V, T_A = 25°C, N = 10

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	C_L = 15pF,	R_L = 280Ω	2	3	4.5	ns
		C_L = 50pF,	R_L = 280Ω		4.5		
t_{PHL}	Propagation delay time, high-to-low-level output	C_L = 15pF,	R_L = 280Ω	2	3	5	ns
		C_L = 50pF,	R_L = 280Ω		5		

S54/N74S03

ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER		TEST CONDITIONS*		MIN	TYP**	MAX	UNIT
V_{IH}	High-level input voltage			2			V
V_{IL}	Low-level input voltage					0.8	V
V_I	Input clamp voltage	V_{CC} = MIN,	I_I = -18mA			-1.2	V
I_{OH}	High-level output current	V_{CC} = MIN, V_{OH} = 5.5V	V_{IL} = 0.8V,			250	μA
V_{OL}	Low-level output voltage	V_{CC} = MIN, I_{OL} = 20mA	V_{IH} = 2V,			0.5	V
I_I	Input current at maximum input voltage	V_{CC} = MAX,	V_I = 5.5V			1	mA
I_{IH}	High-level input current (each input)	V_{CC} = MAX,	V_I = 2.7V			50	μA
I_{IL}	Low-level input current (each input)	V_{CC} = MAX,	V_I = 0.5V			-2	mA
I_{CCH}	Supply current, high-level output (average per gate)	V_{CC} = MAX,	All inputs at 0V		1.5	3.3	mA
I_{CCL}	Supply current, low-level output (average per gate)	V_{CC} = MAX,	All inputs at 5V		5	9	mA

SWITCHING CHARACTERISTICS, V_{CC} = 5V, T_A = 25°C, N = 10

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	C_L = 15pF,	R_L = 280Ω	2	5	7.5	ns
		C_L = 50pF,	R_L = 280Ω		7.5		
t_{PHL}	Propagation delay time, high-to-low-level output	C_L = 15pF,	R_L = 280Ω	2	4.5	7	ns
		C_L = 50pF,	R_L = 280Ω		7		

* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

** All typical values are at V_{CC} = 5V, T_A = 25°C.

† Not more than one output should be shorted at a time, and duration of the short-circuit test should not exceed one second.

NOTES:

A. The pulse generator has the following characteristics: $V_{in(1)}$ = 3V, $V_{in(0)}$ = 0V, t_1 = t_0 = 2.5ns, PRR = 1 MHz, duty cycle = 50%, and $Z_{out} \approx 50\Omega$.

B. Inputs not under test are at 2.7V.

C. C_L includes probe and jig capacitance.